Transaction Information

Wafer Size	200 mm
Fab Section	Metrology

General Product Information

Vendor Supplier	KLA Tencor
Model	AIT II
Vintage	2000
Asset Description	AIT II w/ ADC. Defect Inspection Tool
Software Version	5.3.17
CIM	SECS, GEM
Process	Defect Inspection for Semiconductors

Hardware Configuration

System Type	Description	Quantity
Main System	Defect Inspection	1
Handler System	Dual	
Others		
Factory Interface	Open Cassette	1
Options System		

Excluded Items List (Pumps, Chillers & Abatement are all excluded)

Description	Quantity
NONE	

** List above may or may not be comprehensive. Tool is sold in "as-is" condition. To ensure your satisfaction, we strongly recommend making an appointment to inspect this and every tool you are interested in.*